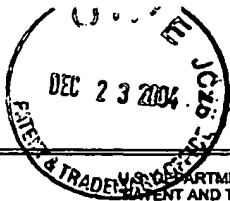


Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 246443US2CONT		SERIAL NO. NEW CONT. APPLICATION	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yukio TANIGUCHI, et al.			
				FILING DATE HEREWITH		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL	AA	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>DL</i>	AO	EP 1 047 119 A2	10/25/200	EUROPEAN PATENT OFFICE	X		
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<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
<i>DA</i>	AW	Mitsuru NAKATA et al., "A New Nucleation-Site-Control Excimer-Laser-Crystallization method, Jpn. J. Appl. Phys. Vol. 40 (2001), pp. 3049-3054					
<i>EA</i>	AX	Chang-Ho et al., "A Novel Phase-Modulated Excimer-Laser Crystallization Method of Silicon Thin Films, Jpn. J. Appl. Phys. Vol. 37 (1998) pp. L492-L495					
<i>EL</i>	AY	International Search Report 9/24/04					
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner <i>A. Dosas</i>					Date Considered 4/26/06		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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246443US2CONTSERIAL NO.  
10/734,248

## LIST OF REFERENCES CITED BY APPLICANT

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December 15, 2003GROUP  
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<i>EC</i>	AA	6,248,606	06/19/2001	Masumitsu INO, et al.			
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>EA</i>	AO	0 035 561	09/16/1981	EUROPE		
	AP					
	AQ					
	AR					
	AS					
	AT					
	AU					
	AV					

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

*J. J. Rosasco*

Date Considered

4/27/06

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